


<b>Search Notes</b> 	<b>Application/Control No.</b> 10642760	<b>Applicant(s)/Patent Under Reexamination</b> TSUCHIYA ET AL.
	<b>Examiner</b> Chawan, Sheela C	<b>Art Unit</b> 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	145,144,149,318,147,270,199, 151	3/19/07	SCC
250	208.1, 548, 559.4	"	"
356	394,390,237.1, 237.4	"	"
716	19,21,	"	"
348	126,130,61, 125, 129	"	"
382	144, 218	9/11/07	SCC
356	394, 237.4	9/11/07	SCC
348	130	9/11/07	SCC
ABOVE SEARCH UP-DATE.		9/11/07	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATABASE, SEE THE SEARCH HISTORY.	3/19/07	SCC
INVENTOR NAME SEARCH.	"	"
SEARCH EAST AND OTHER DATABASES, SEE ATTACHED SEARCH HISTORY.	9/11/07	SCC
382/144, 145,149, 318, 147, 270, 199,151.CCLS. US-PATENT ONLY, SEE TEXT SEARCH.	9/11/07	SCC
250/208.1, 548, 559.4, CCLS.	9/11/07	SCC
"		
356/394,390, 237.1, 237.4.CCLS.	9/11/07	SCC
"		
348/126, 130, 61, 125, 129.CCLS.	9/11/07	SCC
"		
716/19,21.CCLS.	9/11/07	SCC
"		
INTERFERENCE SEARCH SEE SEARCH HISTORY PRINT OUT.	9/11/07	SCC
SEARCH IEEE OR INSPEC DATABASES.	9/11/07	SCC
ABOVE SEARCH UP-DATE.	9/11/07	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	144, 218	9/11/07	SCC

## INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
356	394, 237.4	9/11/07	SCC
348	130	9/11/07	SCC